# NE5020

### DESCRIPTION

The NE5020 is a microprocessor-compatible monolithic 10-bit digital to analog converter subsystem. This device offers 10-bit resolution and  $\pm 0.1\%$  accuracy and monotonicity guaranteed over full operating temperature range.

Low loading latches, adjustable logic thresholds and addressing capability allow the NE5020 to directly interface with most microprocessor and logic controlled systems.

The NE5020 contains internal voltage reference, DAC switches and resistor ladder. Also, the input buffer and output summing amplifier are included. In addition, the matched application resistors for scaling either unipolar or bipolar output values are included on a single monolithic chip.

The result is a near minimum component count 10-bit resolution DAC system.

### FEATURES

- 10-bit resolution
- Guaranteed monotonicity over operating range
- ±0.1% relative accuracy
- Unipolar (OV to +10V) and
- Bipolar (±5V) output range
  Logic bus compatible
- 5µsec settling time

### APPLICATIONS

- Precision 10-bit D/A converters
- 10-bit Analog to Digital converters
- Programmable power supplies
- Test equipment
- Measurement instruments

## PIN CONFIGURATION







### ABSOLUTE MAXIMUM RATINGS

	PARAMETER	RATING	UNIT
Vcc+	Positive supply voltage	18	V
Vcc-	Negative supply voltage	-18	v
VIN	Logic input voltage	0 to 18	V
VREF IN	Voltage at +VREF input	12	v
VREF ADJ	Voltage at VREF adjust	0 to VREF	v
VSUM	Voltage at sum node	12	v
REFSC	Short-circuit current		
	to ground at VREF OUT	Continuous	
OUTSC	Short-circuit current to ground		
	or either supply at VOUT	Continuous	
PD	Power dissipation*		
-	-N package	800	mW
	F package	1000	mW
TA	Operating temperature range		
	NE5020	0 to +70	°C
TSTG	Storage temperature range	-65 to +150	°C
TSOLD	Lead soldering temperature		
	(10 seconds)	300	°C

•NOTES

For N package, derate at 120°C/W above 35°C

For F package, derate at 75°C/W above 75°C

### DC ELECTRICAL CHARACTERISTICS

 $V_{CC}+=+15V,\,V_{CC}-=-15V,\,0^\circ C \leq T_A \leq 70^\circ C$  unless otherwise specified.1 Typical values are specified at 25°C

PARAMETER			NE5020			
		TEST CONDITIONS	Min	Тур	Max	UNIT
	Resolution Monotonicity Relative accuracy				10 10 ±0.1	Bits Bits %FS
V <sub>CC</sub> + V <sub>CC</sub> -	Positive supply voltage Negative supply voltage		11.4 -11.4	15 	16.5 16.5	v v
VIN(1) VIN(0)	Logic "1" input voltage Logic "0" input voltage	Pin 1 = 0V Pin 1 = 0V	2.0		0.8	v v
<sup>I</sup> IN(1) <sup>I</sup> IN(0)	Logic "1" input current Logic "0" input current	Pin 1 = 0V, $2V < V_{IN} < 18V$ Pin 1 = 0V, $-5V < V_{IN} < 0.8V$		0.1 -2.0	10 10	μΑ μΑ
VFS VFS Vzs	Full scale output voltage Full scale output voltage Zero scale voltage	Unipolar operation VREF IN = 5.000V, T <sub>A</sub> = 25°C Bipolar operation VREF IN = 5.000V, T <sub>A</sub> = 25°C Unipolar operation	9.5 4.5 -5.040 -30	9.9902 4.9902 -5.000 5	10.5 5.5 -4.960 +30	V V mV
los	Output short circuit current	T <sub>A</sub> = 25°C V <sub>OUT</sub> = 0V		± 15	± 40	mA
	Output power supply rejection (+) Output power supply rejection (-)	V- = -15V, 13.5V≤V+≤16.5V, external VREF IN = 5.000V V+ = 15V, -13.5V≤V-≤-16.5V, external VREF IN = 5.000V		.001 .001	.01 .01	%FS/ %VS %FS/ %VS
TC <sub>FS</sub> TC <sub>ZS</sub>	Full scale temperature coefficient Zero scale temperature coefficient	VREF IN = 5.000V		20 5		ppmFS /°C ppmFS /°C

NOTE

1. Refer to Figure 2.

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DC ELECTRICAL CHARACTERISTICS (Cont'd)  $V_{CC}$ + = +15V,  $V_{CC}$ - = -15V, 0°C  $\leq$  T<sub>A</sub>  $\leq$  70°C unless otherwise specified.<sup>1</sup> Typical values are specified at 25°C

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PARAMETER			TEST CONDITIONS Min Typ Max		NE5020	
		TEST CONDITIONS			Max	UNIT
IREF <sup>2</sup> IREF SC	Reference output current Reference short circuit current	T <sub>A</sub> = 25°C VREF OUT = 0V		15	3 30	mA mA
PSR+REF	Reference power supply rejection (+)	$V- = -15V, 13.5V \le V+ \le 16.5V,$ IREF = 1.0mA		.003	.01	%VR/ %VS
PSR-REF	Reference power supply rejection (-)	$V+ = 15V, -13.5V \le V- \le 16.5V,$		.003	.01	%VR/ %VS
VREF TC <sub>REF</sub>	Reference voltage Reference voltage temperature coefficient	$I_{REF} = 1.0mA, T_A = 25^{\circ}C$ $I_{REF} = 1.0mA$	4.9	5.0 60	5.25	V ppm/°C
Z <sub>IN</sub>	DAC VREFIN input impedance	IREF = 1.0mA		5.0		kΩ
Icc+	Positive supply current	$V_{CC}$ + = 15V		7	14	mA
Icc-	Negative supply current	$V_{\rm CC} = -15V$		- 10	-15	mA
PD	Power dissipation	$I_{REF} = 1.0 mA, V_{CC} = \pm 15 V$		255	435	mW

NOTE

1. Refer to Figure 2.

2. For IREF OUT greater than 3mA, an external buffer is required.

## AC ELECTRICAL CHARACTERISTICS <sup>3</sup> $V_{CC} = \pm 15V$ , $T_A = 25^{\circ}C$

					NE5020			
PARAMETER		то	FROM	TEST CONDITIONS	Min	Тур	Max	UNIT
TSLH TSHL	Settling time Settling time	± ½ LSB ± ½ LSB	input Input	All bits low to high <sup>4</sup> All bits high to low <sup>5</sup>		5 5		μs μs
<sup>t</sup> pih <sup>t</sup> phi <sup>t</sup> pisb <sup>t</sup> pih <sup>t</sup> phi	Propagation delay Propagation delay Propagation delay Propagation delay Propagation delay	Output Output Output Output Output	Input Input Input LE LE	All bits switched low to high <sup>4</sup> All bits switched high to low <sup>5</sup> 1 LSB change <sup>4,5</sup> low to high transition <sup>6</sup> high to low transition <sup>7</sup>		300 150 150 300 150		ns ns ns ns ns
t <sub>s</sub> th tpw	Set-up time Hold time Latch enable pulse width	LE Input	Input LE	3, 8 3, 8 3, 8	100 50 150			ns ns ns

NOTES

3. Refer to Figure 3.

4. See Figure 6.

5. See Figure 7.

6. See Figure 8.

7. See Figure 9. 8. See Figure 10.

### DC PARAMETRIC TEST CONFIGURATION AC PARAMETRIC TEST CONFIGURATION γvcc+ O VCC+ MSB LSB MSB LSB <u></u> Ξ 0.47μF EE2 LE1 <u></u> Ξ 0.47μF LE2 LE1 9999999 9999999999 111098765432 111098765432 21 5.000V DIG GND DIG. GND 12 13 17 ANA. GND 24 VDEE IN ANA. GND 2 17 -15 VREF OUT VREE IN 1 15 VREF IN 5020 OUTPUT 5020 ~ 14 30n8 OUTPUT 0 30n VOUT 20 VOUT 20 0 SUM 22 SUM 22 5K ⋨ AMP 23 COMP. AMP 23 COMP. 19 18 19 18 1N914 100 ΗĻ 0.1.... 0.1.F Y Vcc-Figure 3 Figure 2 FULL/ZERO SCALE ADJUST-UNIPOLAR OUTPUT (0-10V) **BIPOLAR OUTPUT OPERATION (-5 to +5V)** Vcc+ MSB LSB MSB LSB LE2 LE1 Ţ LE2 LE1 I 0.47 0.47<sub>//</sub>F 9999999 111098765432 110 8765 4 3 2 21 DIG. GND DIG. GND 12 13 17 13 ANA. GND 24 VREE IN VREF IN ANA. GND 2 15 VREF OUT 15 VREF OUT -VREE IN 16 - VREF IN 16 5020 5020 10K OUTPUT 10K 14 VREF ADJ OUTPUT 4 VREF ADJ 30nF 10T VOUT 20 80K 101 VOUT 20 BOK SUM 22 SUM 22 5K AMP 23 COMP. AMP 23 COMP. FULL SCALE BIP OFF 18 19 19 ÷ Ē Y Vcc 20K 0.1#F 9 Vcc+ 0.1.E 10T Ī 1.0 ZERO SCALE Y 20K ADJUST Vcc-6 Vcc-101 FULL SCALE 2 vcc-Figure 4 Figure 5 ADJUST SETTLING TIME AND PROPAGATION DELAY, SETTLING TIME AND PROPAGATION DELAY, LOW TO HIGH DATA HIGH TO LOW DATA DATA DATA TSHI TSLF TPHL 107 OUTPUT OUTPUT ٥v 1 LSB 01 LE = LOW LE = LOW

Figure 7

Figure 6

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**PROPAGATION DELAY, LATCH ENABLE TO OUTPUT** 

### DATA DATA LE Î.E **TPLH** 100 107 OUTPUT OUTPUT 01 OV Figure 8 Figure 9 LATCH ENABLE PULSE WIDTH, SET-UP AND HOLD TIMES LE DATA Figure 10 PMOS VTH = 0V VTH = VPIN 1 + 1.4V + 15V CMOS, HTL, HNIL VTH = +7.6V TTL. DTL VTH = +1.4V 文 Ŧ + 12V TO + 15V O + 15V 0 IN4 148 φ 10K 10 9.1KΩ NE5020 O PIN 1 0 PIN 1 O PIN 1 6.2V ZENER O DIG GND (PIN 1) 6.2KΩ **Š** 0.1µF ş 10K1! Δ th d, th th 9 5V 10 - 10V NOTE DO NOT EXCEED NEGATIVE LOGIC INPUT RANGE OF DAC +5V CMOS VTH = +2.8V + 10V CMOS VTH = +5 0V 10K ECL VTH≥ -1.29V Q +10V 9 +54 늪 1.3K 12 ş ş 3.6KΩ 6.2K! 2N3904 O PIN 1 O PIN 1 IN4 148 0.1µF 3.6КΩ ₹ IN4148 3.9KΩ ₹ O PIN A A IKΩ 6 -5.2V Figure 11

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**PROPAGATION DELAY, LATCH ENABLE TO OUTPUT** 

### CIRCUIT DESCRIPTION

The NE5020 provides ten data latches, an internal voltage reference, application resistors, and a scaled output voltage, in addition to the basic DAC components (see block diagram, figure 1).

### Latch Circuit

Digital interface with the NE5020 is readily accomplished through the use of two latch enable ports ( $\overline{LE}_1$  and  $\overline{LE}_2$ ) and ten data input latches. LE2 controls the two most significant bits of data (DBg and DBg) while LE1 controls the eight lesser significant bits (DB7 through DBd). Both the latch enable ports (LE) and the data inputs are static and threshold sensitive. When the latch enable ports (LE) are high (Logic '1') the data inputs become very high impedances and essentially disappear from the data bus. Addressing the LE with a low (Logic '0') the latches become active and adapt the logic states present on the data bus. During this state, the output of the DAC will change to the value proportional to the data bus value. When the latch enable returns to a high state, the selected set of data inputs (i.e., depending on which LE goes high) memorize' the data bus logic states and the output changes to the unique output value corresponding to the binary word in the latch.

The data inputs are inactive and high impedance (typically requiring  $-2\mu A$  for low (.8V max) or 0.1 $\mu A$  for high (2.0V min)) when the  $\overline{LE}$  is high. Any changes on the data bus with  $\overline{LE}$  high will have no effect on the DAC output.

The digital logic inputs ( $\overline{LE}$  and DB) for the NE5020 utilize a differential input logic system with a threshold level of + 1.4 volts with respect to the voltage level on the digital ground pin (Pin 1). Figure 11 details several bias schemes used to provide the proper threshold voltage levels for various logic families.

To be compatible with a bus orientated system the DAC should respond in as short a period as possible to insure full utilization of the microprocessor, controller and I/O control lines. Figure 10 shows the typical timing requirements of the latch and data lines. This figure indicates that data on the data bus should be stable for at least 50nsec after LE is changed to a high state.

The independent  $\overline{LE}$  ( $\overline{LE}_1$  and  $\overline{LE}_2$ ) lines allow for direct interface from an 8 bit data bus (see figure 12). Data for the two MSB's is supplied and stored when  $\overline{LE}_2$  is activated low and returned high according to the NE5020 timing requirements. Then  $\overline{LE}_1$  is activated low and the remaining eight LSB's of data are transferred into the DAC. With

LE<sub>1</sub> returning high the loading of ten bit data word from an eight bit data bus is complete.

Occasionally the analog output must change to its data value within one data address operation. This is no problem using the NE5020 on a 16 bit bus or any other data bus with 10 or greater data bits. This can be accomplished from an 8 bit data bus by utilizing an external latch circuit to preload the two MSB data values. Figure 13 shows the circuit configuration.

After preloading (via LE pre-load) the external latch with the two MSB values,  $LE_2$  is activated low and the eight LSB's and the





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two MSB's are concurrently loaded into the DAC in one address operation. This permits the DAC output to make its appropriate change at one time.

### **Reference Interface**

The NE5020 contains an internal bandgap voltage reference which is designed to have a very low temperature coefficient and excellent long term stability characteristics.

The internal bandgap reference (1.23V) is buffered and amplified to provide the 5 volt reference output. Providing a V<sub>REF</sub>ADJ (pin 14) allows trimming of the reference output. Utilization of the adjust circuit shown in figure 16 performs not only V<sub>REF</sub> adjustment but also full scale output adjust. Notice that the V<sub>REF</sub>ADJ pin is essentially the sum node of an op amp and is sensitive to excessive node capacitance. Any capacitance on the node can be minimized by placing the external resistors as close as possible to the V<sub>REF</sub>ADJ pin and observing good layout practices.

The VREF out node can drive loads greater than the DAC VREF input requirements and can be used as an excellent system voltage reference. However, to minimize load effects on the DAC system accuracy, it is recommended that a buffer amplifier is used.

### **Input Amplifier**

The DAC reference amplifier is a high gain internally compensated op amp used to convert the input reference voltage to a precision bias current for the DAC ladder network.

Figure 1 details the input reference amplifier and current ladder. The voltage to current converter of the DAC amp will generate a 1mA reference current through Q<sub>R</sub> with a 5 volt V<sub>REF</sub>. This current sets the input bias to the ladder network. Data bit 9 (DB<sub>9</sub>)(Q<sub>9</sub>), when turned on, will mirror this current and will contribute 1mA to the output. DB<sub>8</sub> (Q<sub>8</sub>) will contribute % of that value or 0.5mA and so on. These current values act as current sinks and will add at the sum node to produce a DAC ladder to sum node function of:

$$I_{OUT} = \frac{2V_{REF}}{R_{REF}} \quad \left(\frac{DB9}{2} + \frac{DB8}{4} + \frac{DB7}{8} + \frac{DB6}{16} + \frac{DB5}{32} + \frac{DB4}{64} + \frac{DB3}{128} + \frac{DB2}{256} + \frac{DB1}{512} + \frac{DB0}{1024}\right) \ .$$

Because of the fixed internal compensation of the reference amp, the slew rate is limited to typically  $0.7V/\mu$ sec and source impedances at the VREF INPUT greater than 5k\Omega should be avoided to maintain stability. The  $-V_{\text{REF}}$  INPUT pin is uncommitted to allow utilization of negative polarity reference voltages. In this mode  $+V_{\text{REF}}$  INPUT is grounded and the negative reference is tied directly to the  $-V_{\text{REF}}$  INPUT. The  $-V_{\text{REF}}$  INPUT contains a 5k $\Omega$  resistor that matches a like resistor in the  $+V_{\text{REF}}$  INPUT to reduce voltage offset caused by op amp input bias currents.

### **Output Amplifier and Interface**

The NE5020 provides an on chip output op amp to eliminate the need for additional external active circuits. Its two stage design with feed forward compensation allows it to slew at 15V/µsec and settle to within ± %LSB in 5µsec. These times are typical when driving the rated loads of  $R_L \ge 5k$  and  $C_L \leq 50 pF$  with recommended values of CFF = 1nF and CFB = 30pF. Typical input offset voltages of 5mV and 50k open loop gain insure an accurate current to voltage conversion is performed when using the on chip RFB resistor. RFB is matched to RREF and RBIP to maintain accurate voltage gain over operating conditions. The diode shown from ground to sum node prevents the DAC current switches from saturating the op amp during large signal transitions which would otherwise increase the settling time.

The output op amp also incorporates output short circuit protection for both positive and negative excursions. During this fault condition  $I_{OUT}$  will limit at  $\pm$  15mA typical. Recovery from this condition to rated accuracy will be determined by duration of short circuit and die temperature stabilization.

### **Bipolar Output Voltage**

The NE5020 includes a thermally matched resistor, RBIP, to offset the output voltage by 5 volts to obtain -5V to +5V output voltage range operation. This is accomplished by shorting pins 18 and 22 (see figure 14). This connection produces a current equal to (VREF IN - Vsum node) + RBIP, (1mA nominal), which is injected into the sum node. Since full scale current out is approximately 2mA (1.9980mA), (2mA - 1mA)5k = 5V will appear at the output. For zero DAC output currents, 1mA is still injected into sum mode and  $V_{OUT} = -(5k)(1mA) = -5V$ . Zero scale adjust and full scale adjust are performed as described below, noting that full scale voltage is now approximately +5 volts, zero scale adjust may be used to trim VOUT = 0.00 with the MSB high or  $V_{OUT} = -5.0V$ with all bits off.

### Zero Scale Adjustment

The method of trimming the small offset error that may exist when all data bits are low is shown in figure 15. The trim is the result of injecting a current from resistor R<sub>2</sub> that counteracts the error current. Adjusting potentiometer R<sub>1</sub> until V<sub>OUT</sub> equals 0.000 volts in the unipolar mode or -5.000 volts in the bipolar mode (see bipolar section) accomplishes this trim.

### **Full Scale Adjustment**

A recommended full scale adjustment circuit when using the internal voltage reference is shown in figure 16. Potentiometer R<sub>3</sub> is adjusted until  $V_{OUT}$  equals 9.99023V. In many applications where the absolute accu-



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racy of full scale is of low importance when compared to the other system accuracy factors, then this adjustment circuit is optional. they match and track in value closely over wide ambient temperature variations. Typical matching is less than  $\pm 0.3\%$  which implies that typical full scale (or gain) error is less than  $\pm 0.3\%$  of ideal full scale value.

As resistors  ${\sf R}_{REF},\,{\sf R}_{fb}$  and  ${\sf R}_{BIP}$  shown in figure 1 are integrated in close proximity,



